

The industry's most efficient CHUCK system, test efficiency significantly improved

- High efficient CHUCK test system, running speed \geq 40mm/s, motion precision $\leq\pm1\mu\text{m}$, while moving the translocation time index time 500ms, excellent system operating parameters have reached the highest level of the industry, ultra-high test accuracy and efficiency to meet all kinds of wafers and devices of high repeatability and stability test, test efficiency significantly improved
- Temperature control accuracy and stability better than $\pm0.1^\circ\text{C}$, providing reliability wafer testing in high and low temperature environments
- The compact structure design of four-dimensional motion with low center of gravity ensures the motion speed of 40mm/s while maintaining the stability of motion acceleration and deceleration

5) High And Low Temperature Vacuum Probe Station

Product Overview

CG launched series is the first domestic company independent research and development of high and low temperature vacuum prober, in ultra high vacuum, automatic control, laser simulation plays a SEMISHARER unique technical advantages, is an innovative SEMISHARE technology accumulated for years.

Basic Information

Product number	CG-O-4	working environment	High and low temperature vacuum environment
electricity demand	AC220V,50~60HZ	Control method	Manual Probe Station
Product Size	1100mm*1100mm*530mm	equipment weight	About 190 kg

Application direction

Chip test LD/LED/PD test Optical fiber spectral characteristics Test MATERIAL/device IV/CV characteristics Test Hall test electromagnetic transport characteristics high frequency characteristics test, etc.

Technical characteristics